

DATA SHEET



## N-Channel Silicon MOSFET **2SK3284** — General-Purpose Switching Device **Applications**

## Features

- · Low ON-resistance.
- Low Qg.
- Ultrahigh-speed switching.

## Specifications

#### Absolute Maximum Ratings at Ta=25°C

Parameter	Symbol	Conditions	Ratings	Unit
Drain-to-Source Voltage	VDSS		400	V
Gate-to-Source Voltage	VGSS		±30	V
Drain Current (DC)	۱D		10	A
Drain Current (Pulse)	IDP	PW≤10µs, duty cycle≤1%	40	A
Allowable Power Dissipation	PD	Tc=25°C	50	W
Channel Temperature	Tch		150	°C
Storage Temperature	Tstg		-55 to +150	°C

#### Electrical Characteristics at Ta=25°C

Parameter	Symbol	Conditions		Ratings		
			min	typ	max	Unit
Drain-to-Source Breakdown Voltage	V(BR)DSS	ID=1mA, VGS=0V	400			V
Zero-Gate Voltage Drain Current	IDSS	V <sub>DS</sub> =320V, V <sub>GS</sub> =0V			1.0	mA
Gate-to-Source Leakage Current	IGSS	V <sub>GS</sub> =±30V, V <sub>DS</sub> =0V			±100	nA
Cutoff Voltage	VGS(off)	VDS=10V, ID=1mA	3		4	V
Forward Transfer Admittance	yfs	V <sub>DS</sub> =10V, I <sub>D</sub> =6A	2.9	5.8		S
Static Drain-to-Source On-State Resistance	R <sub>DS</sub> (on)	ID=6A, VGS=15V		0.43	0.55	Ω
Input Capacitance	Ciss	VDS=20V, f=1MHz		1150		pF
Output Capacitance	Coss	V <sub>DS</sub> =20V, f=1MHz		350		рF
Reverse Transfer Capacitance	Crss	V <sub>DS</sub> =20V, f=1MHz		150		pF
Total Gate Charge	Qg	VDS=200V, VGS=10V, ID=10A		40		nC
Turn-ON Delay Time	t <sub>d</sub> (on)	See specified Test Circuit.		17		ns
Rise Time	tr	See specified Test Circuit.		30		ns
Turn-OFF Delay Time	t <sub>d</sub> (off)	See specified Test Circuit.		150		ns
Fall Time	tf	See specified Test Circuit.		50		ns
Diode Forward Voltage	VSD	IS=10A, VGS=0V			1.2	V

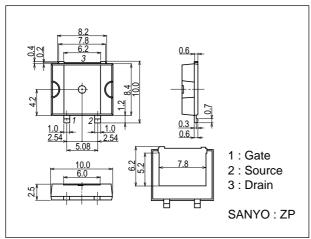
Note) Although the protection diode is contained between gate and source, be careful of handling enough.

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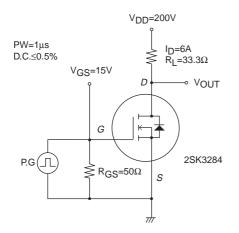
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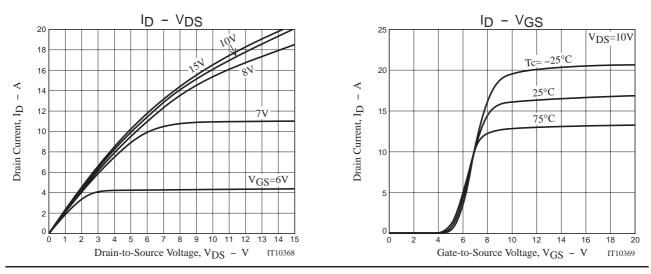
### **Package Dimensions**

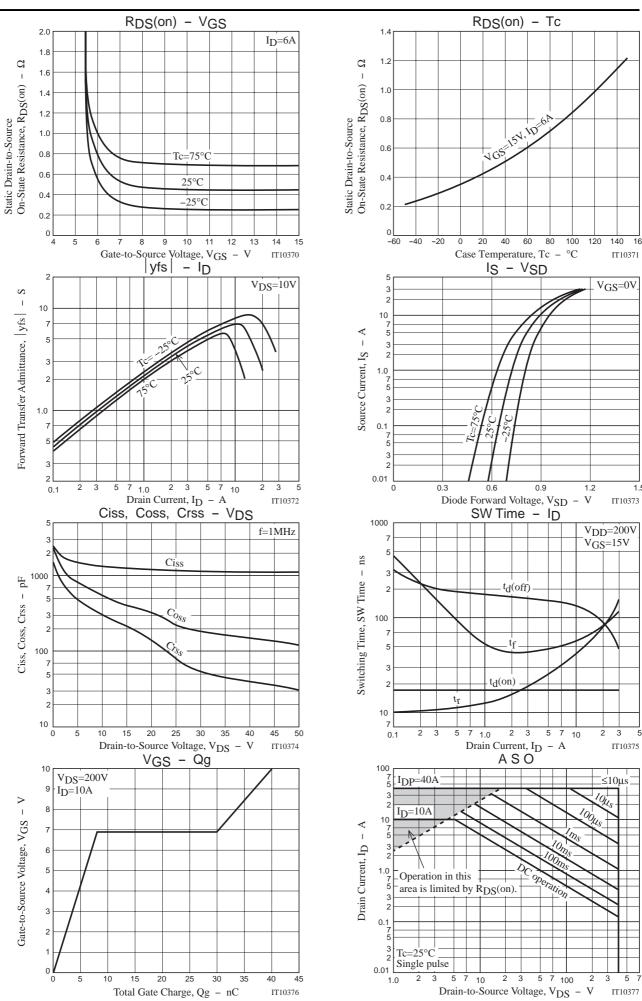
unit : mm 7002-001



## **Switching Time Test Circuit**





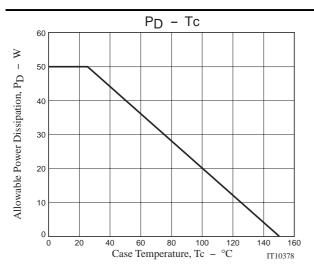


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# Note on usage : Since the 2SK3284 is a MOSFET product, please avoid using this device in the vicinity of highly charged objects.

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